UNITED STATES DEPARTMENT OF COMMERCE United States Patent and Trademark Office Address: COMMISSIONER FOR PATENTS P.O. Box 1450 Alexandria, Virginia 22313-1450 www.uspto.gov

APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
10/032,056	12/31/2001	Byeong-Dae Choi	053785-5045	5637
, - -	7590 10/07/200 VIS & BOCKIUS LLP	EXAMINER		
	LVANIA AVENUE N	W	WARREN, MATTHEW E	
WASHINGTON, DC 20004			ART UNIT	PAPER NUMBER
			2815	
			MAIL DATE	DELIVERY MODE
			10/07/2008	PAPER

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

	Application No.	Applicant(s)	
	10/032,056	CHOI, BYEONG-DAE	
Office Action Summary	Examiner	Art Unit	
	MATTHEW E. WARREN	2815	
The MAILING DATE of this communication ap Period for Reply	pears on the cover sheet with the c	orrespondence address	
A SHORTENED STATUTORY PERIOD FOR REPL WHICHEVER IS LONGER, FROM THE MAILING D. - Extensions of time may be available under the provisions of 37 CFR 1. after SIX (6) MONTHS from the mailing date of this communication. - If NO period for reply is specified above, the maximum statutory period. - Failure to reply within the set or extended period for reply will, by statut Any reply received by the Office later than three months after the mailing earned patent term adjustment. See 37 CFR 1.704(b).	DATE OF THIS COMMUNICATION 136(a). In no event, however, may a reply be tin will apply and will expire SIX (6) MONTHS from e, cause the application to become ABANDONE	N. nely filed the mailing date of this communication. D (35 U.S.C. § 133).	
Status			
Responsive to communication(s) filed on 21 J This action is FINAL . 2b) ☑ This Since this application is in condition for allowed closed in accordance with the practice under the second se	s action is non-final. ance except for formal matters, pro		
Disposition of Claims			
4) ☐ Claim(s) 1-14 and 16-29 is/are pending in the 4a) Of the above claim(s) 16-29 is/are withdra 5) ☐ Claim(s) is/are allowed. 6) ☐ Claim(s) 1-14 is/are rejected. 7) ☐ Claim(s) is/are objected to. 8) ☐ Claim(s) are subject to restriction and/o	wn from consideration.		
	0.5		
9) The specification is objected to by the Examina 10) The drawing(s) filed on is/are: a) accomposed as a composition and a composition and a composition to the separate and a composition and a compositi	cepted or b) objected to by the I drawing(s) be held in abeyance. See ction is required if the drawing(s) is object.	e 37 CFR 1.85(a). jected to. See 37 CFR 1.121(d).	
Priority under 35 U.S.C. § 119			
12) Acknowledgment is made of a claim for foreign a) All b) Some * c) None of: 1. Certified copies of the priority documen 2. Certified copies of the priority documen 3. Copies of the certified copies of the priority documen application from the International Burea * See the attached detailed Office action for a list	ts have been received. ts have been received in Applicationity documents have been receive nu (PCT Rule 17.2(a)).	on No ed in this National Stage	
Attachment(s) 1) Notice of References Cited (PTO-892) 2) Notice of Draftsperson's Patent Drawing Review (PTO-948) 3) Information Disclosure Statement(s) (PTO/SB/08) Paper No(s)/Mail Date	4) Interview Summary Paper No(s)/Mail Da 5) Notice of Informal F 6) Other:	ate	

DETAILED ACTION

This Office Action is in response to the RCE and Amendment filed on July 21, 2008.

Claim Rejections - 35 USC § 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-14 are rejected under 35 U.S.C. 103(a) as being unpatentable over the Applicant's Prior Art Figures 2 and 3F (APAF) in view of Kakuda et al. (US 5,162,933).

In re claim 1, APAF 2 and 3F show an array substrate for a liquid crystal display device, comprising a substrate (22) a plurality of gate lines (25) arranged transversely on the substrate; a plurality of data lines (27) disposed orthogonal to the plurality of gate lines. A plurality of thin film transistors is formed on the substrate adjacent to intersections of the gate lines and the data lines. Each thin film transistor includes a gate electrode (32), a gate insulation layer (41), an active layer (45), an ohmic contact layer (47), a source electrode (33), and a drain electrode (35), the source electrode extended from each of data lines and overlapping a portion of the gate electrode. A plurality of pixel electrodes (17) are disposed at pixel regions (P) defined by the intersections of the gate lines and the data lines wherein each pixel electrode connected to a corresponding one of the drain electrodes. A metal layer (28) is formed at

Application/Control Number: 10/032,056

Page 3

Art Unit: 2815

peripheral portions of the drain electrode to extend from the pixel electrode. The source electrode is positioned between the ohmic contact layer and the metal layer. The APAF shows all of the elements of the claim except the metal layer formed on an entire surface of each of the data lines and the source electrode. Kakuda et al. shows (figs. 3 and 4) an LCD device having data line (11) with a metal layer formed on the entire surface. A source electrode (22) extends from the data line (col. 4, lines 50-53) and is also covered with a metal layer (11b in fig. 4). With such a configuration, the resistance of the data lines is reduced. (col. 7, lines 51-55). Therefore, it would have been obvious to one of ordinary skill in the art at the time the invention was made to modify the data line of the APAF by forming a metal layer on the entire data line as taught by Kakuda to reduce the resistance of the data lines.

In re claims 2 and 11, the APAF shows (fig. 3B) that the gate insulation layer (41) is disposed on the gate electrode or a plurality of gate electrodes as shown in figure 2.

In re claim 3, the APAF shows (fig. 3B) that the active layer (45) is disposed on the gate insulation layer, and the ohmic contact layer (47) is disposed on the active layer.

In re claim 4, the APAF (fig. 3F) shows that the source electrode (33) and the drain electrode (35) are disposed on the ohmic contact layer.

In re claims 5 and 6, the APAF shows (fig. 2) that the source electrode extends from one of the data lines and the drain electrode extends from one of the pixel electrodes.

Art Unit: 2815

In re claim 7-10, the APAF discloses [0009] that the drain electrode and source electrode include at least a transparent conductive material (ITO). Each data line includes at least the transparent conductive material (ITO). Each pixel electrode (17) includes the transparent conductive material (ITO). The transparent conductive material is selected from a group including indium tin oxide, indium zinc oxide, zinc oxide, tin oxide, and indium oxide.

In re claim 12, Kakuda discloses (col. 7, lines 8-28) that the materials of the metal layer are selected from the group including Au, Ag, Cu, and Al.

In re claim 14, the APAF shows (fig. 3F) that the metal layer (28) is formed at peripheral portions of the plurality of pixel electrodes and at peripheral portions of the drain electrode.

Response to Arguments

Applicant's arguments filed with respect to claims 1-14 have been fully considered but they are not persuasive. The applicant primarily asserts that the prior art references do not show all of the elements of the claims, specifically that Kakuda et al. fails to show that the source electrode is positioned between the ohmic contact layer and the metal. The examiner believes that the cited prior art references show all of the elements of the claims. As stated in the rejection above, the APAF already shows that the source electrode is positioned between the ohmic contact layer and the metal. Kakuda is not required to disclose this limitation because Kakuda was only cited to cure the deficiencies of the APAF by showing that the metal layer is formed on the entire

Art Unit: 2815

surface of the data line. Therefore, the 35 USC 103 rejection above is still proper and shall remain.

Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to MATTHEW E. WARREN whose telephone number is (571)272-1737. The examiner can normally be reached on Mon-Thur and alternating Fri 9:00-5:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Kenneth Parker can be reached on (571) 272-2298. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Application/Control Number: 10/032,056 Page 6

Art Unit: 2815

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

/Matthew E Warren/ Primary Examiner, Art Unit 2815

September 28, 2008